

SN74ALS819, SN74ALS29818 8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

- High-Speed 8-Bit Parallel Pipeline Register
- Serial Shadow Register With Right-Shift Only
- 'ALS29818 Performs Parallel-to-Serial and Serial-to-Parallel Conversion
- Designed Specifically for Use in Applications Such As:
 - Write Control Store ('ALS29818)
 - Serial Shadow-Register Diagnostics
- 'ALS819 Provides Even-Parity Output
- Low Power Dissipation . . . 215 mW Typical
- 'ALS29818 is Functionally Equivalent to AMD AM29818
- Package Options include Plastic Small Outline Packages, Standard Plastic DIPs, and Plastic Chip Carriers

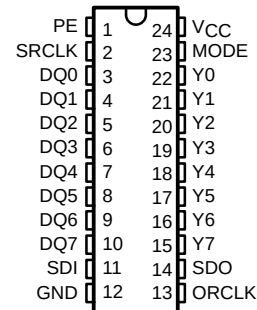
description

The SN74ALS819 and SN74ALS29818 are 8-bit pipeline registers each with an on-chip shadow register. They are for use in applications such as write control store and shadow register diagnostics.

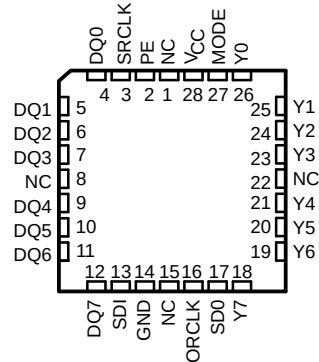
The output registers of the 'ALS819 and 'ALS29818 are loaded in parallel from either the I/O port (DQ0–DQ7) or the shadow register. The shadow register of the 'ALS29818 can be loaded serially or from either the I/O port (Y0–Y7) or the pipeline register. The 'ALS819 shadow register can be loaded serially or from the I/O port (DQ0–DQ7). In addition, the 'ALS819 provides a Parity-Even (PE) output, which monitors parity of the output register. Operation of these devices is controlled by the Mode and SDI inputs as shown in the function table.

The SN74ALS819 and SN74ALS29818 are characterized for operation from 0°C to 70°C.

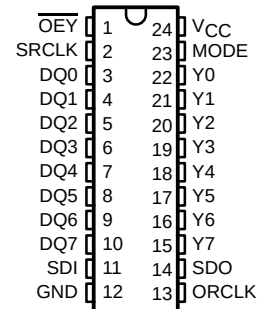
SN74ALS819 . . . DW OR JT PACKAGE
(TOP VIEW)



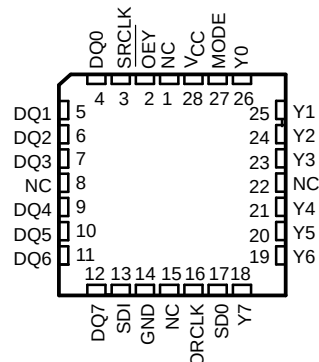
SN74ALS819 . . . FN PACKAGE
(TOP VIEW)



SN74ALS29818 . . . DW OR NT PACKAGE
(TOP VIEW)



SN74ALS29818 . . . FN PACKAGE
(TOP VIEW)



NC – No internal connection

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

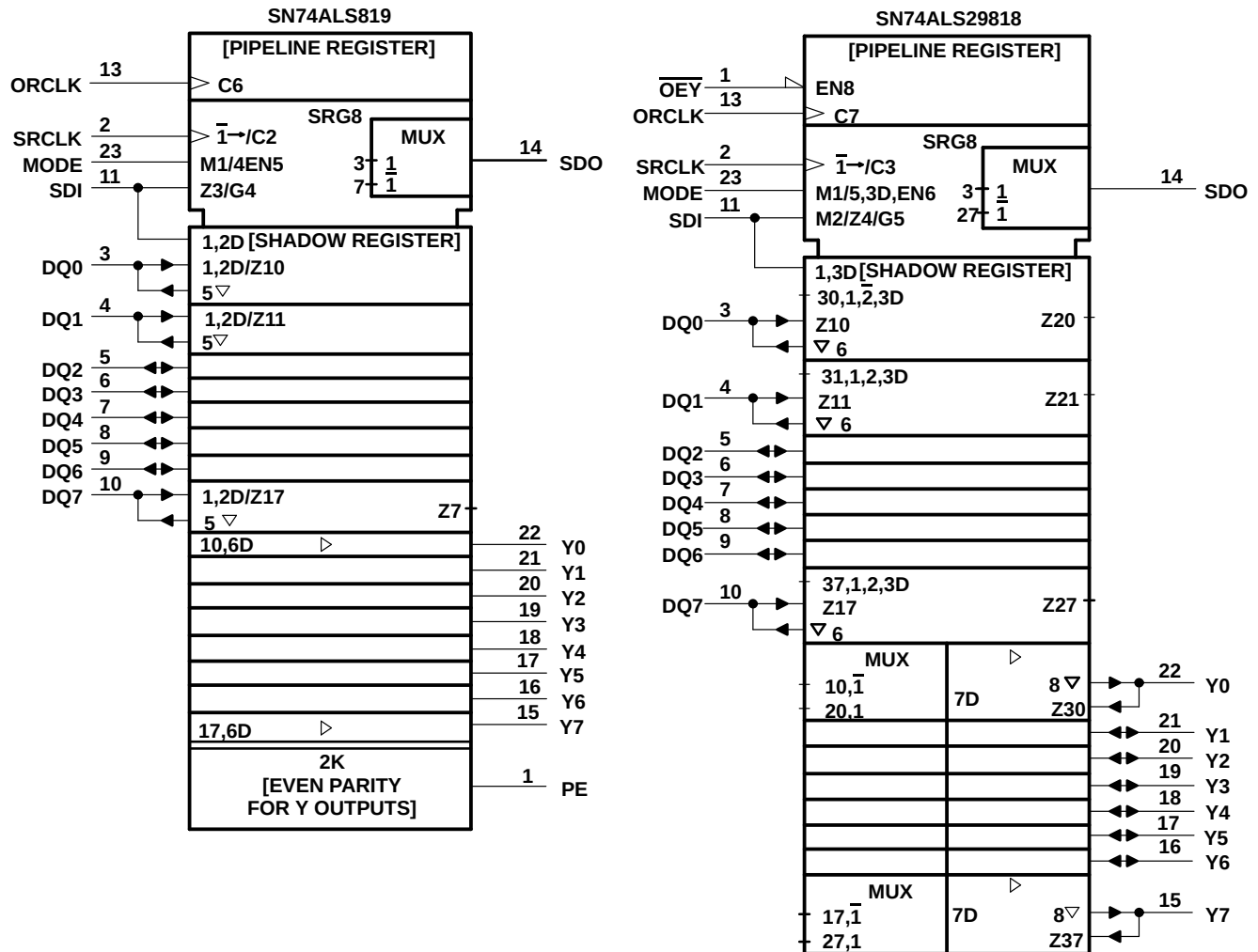
Copyright © 1986, Texas Instruments Incorporated

SN74ALS819, SN74ALS29818

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

logic symbols†

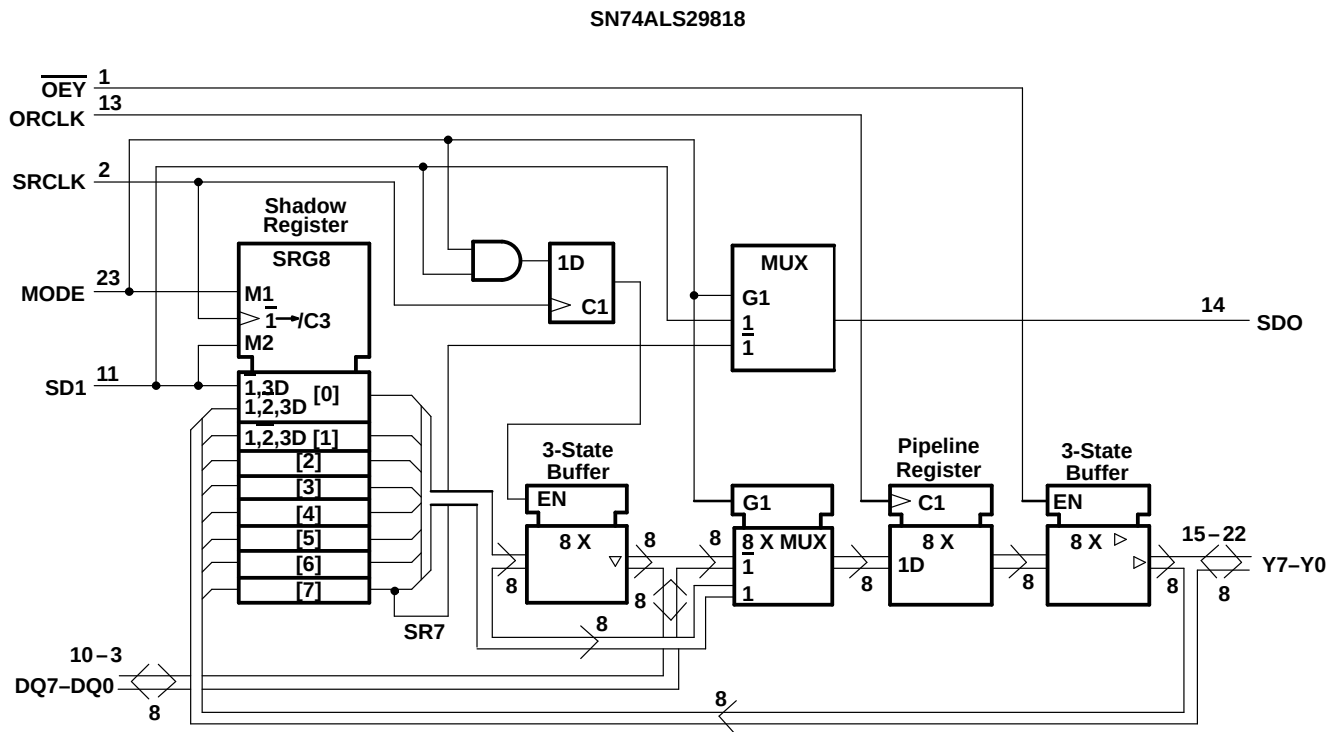
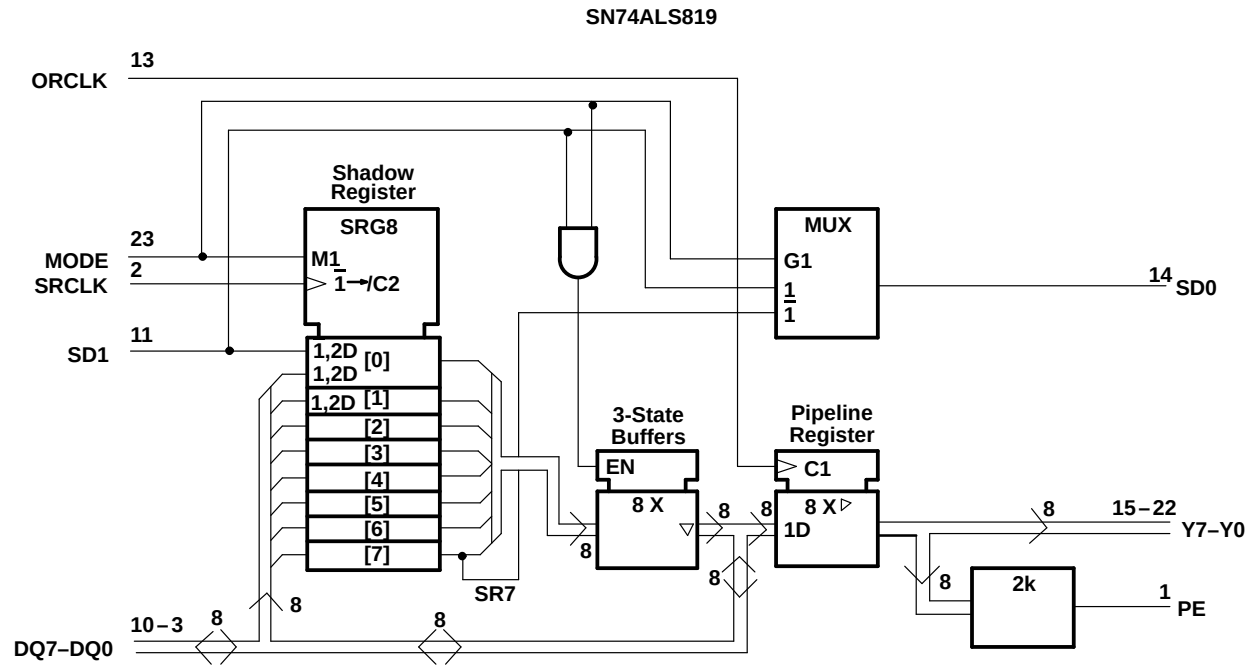


† These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for DW and NT packages.

SN74ALS819, SN74ALS29818 8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

logic diagrams (positive logic)



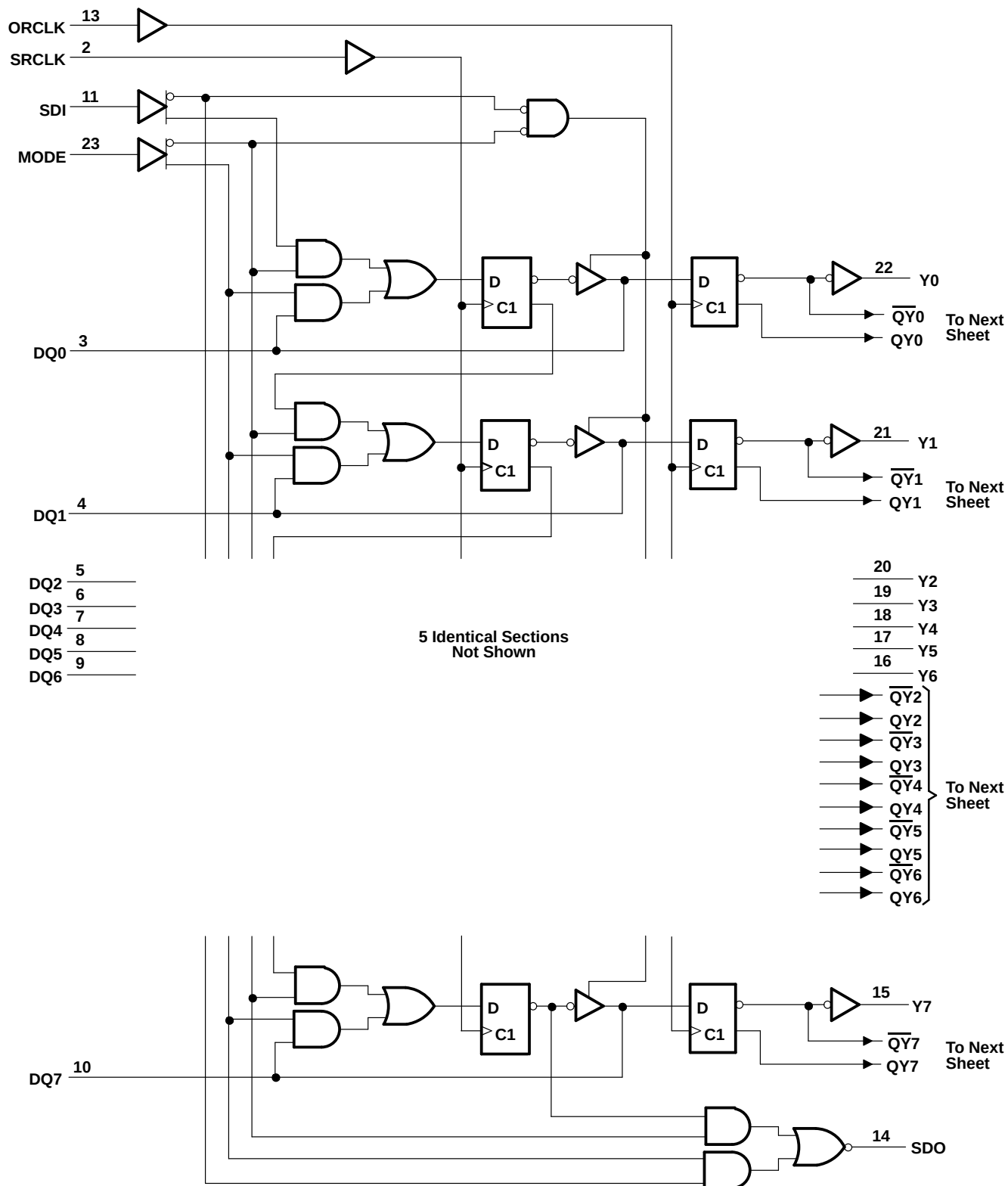
Pin numbers shown are for DW and NT packages.

SN74ALS819

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

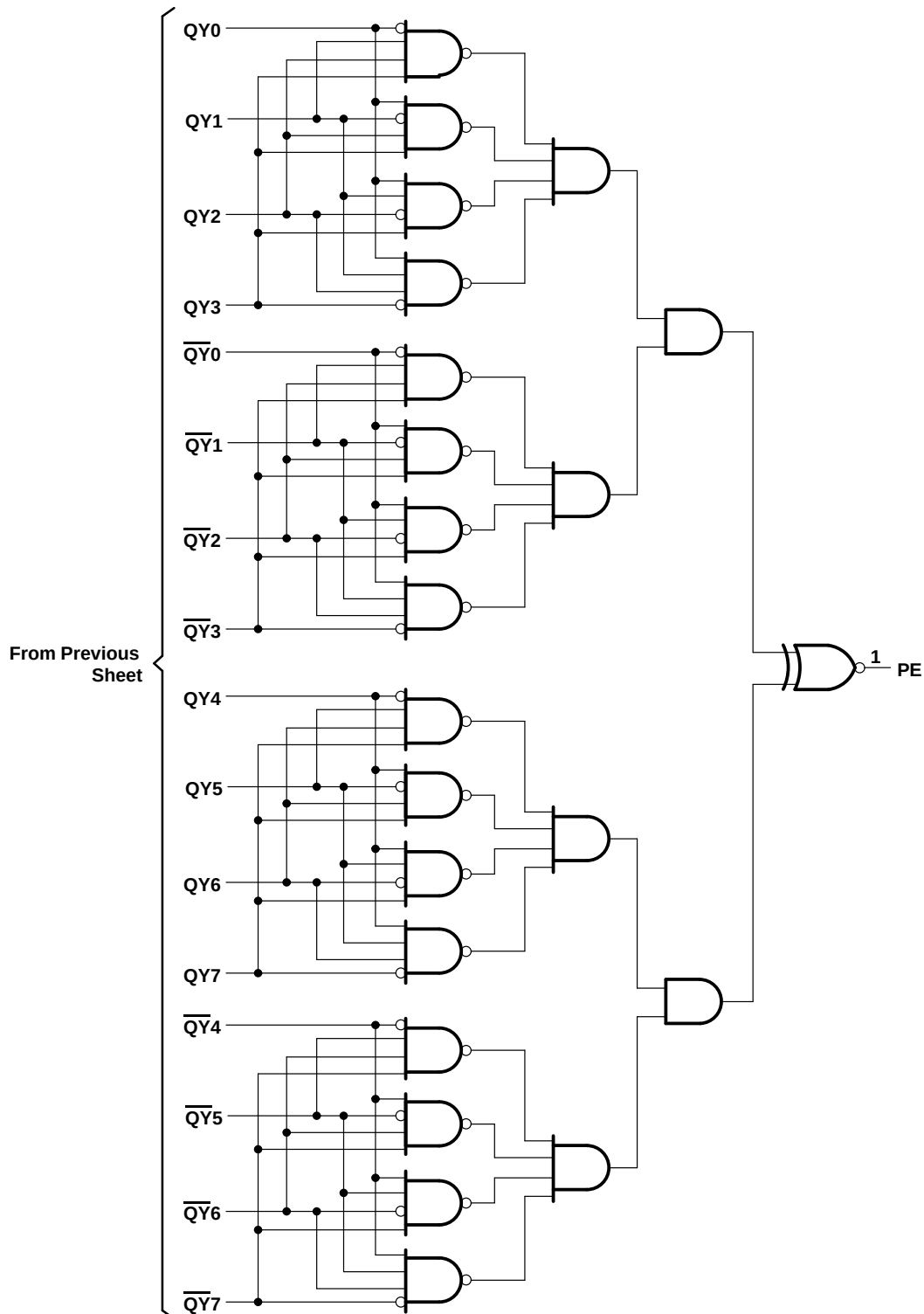
SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

SN74ALS819 gate-level logic diagram (positive logic)



Pin numbers shown are for DW and NT packages.

SN74ALS819 gate-level logic diagram (positive logic) (continued)



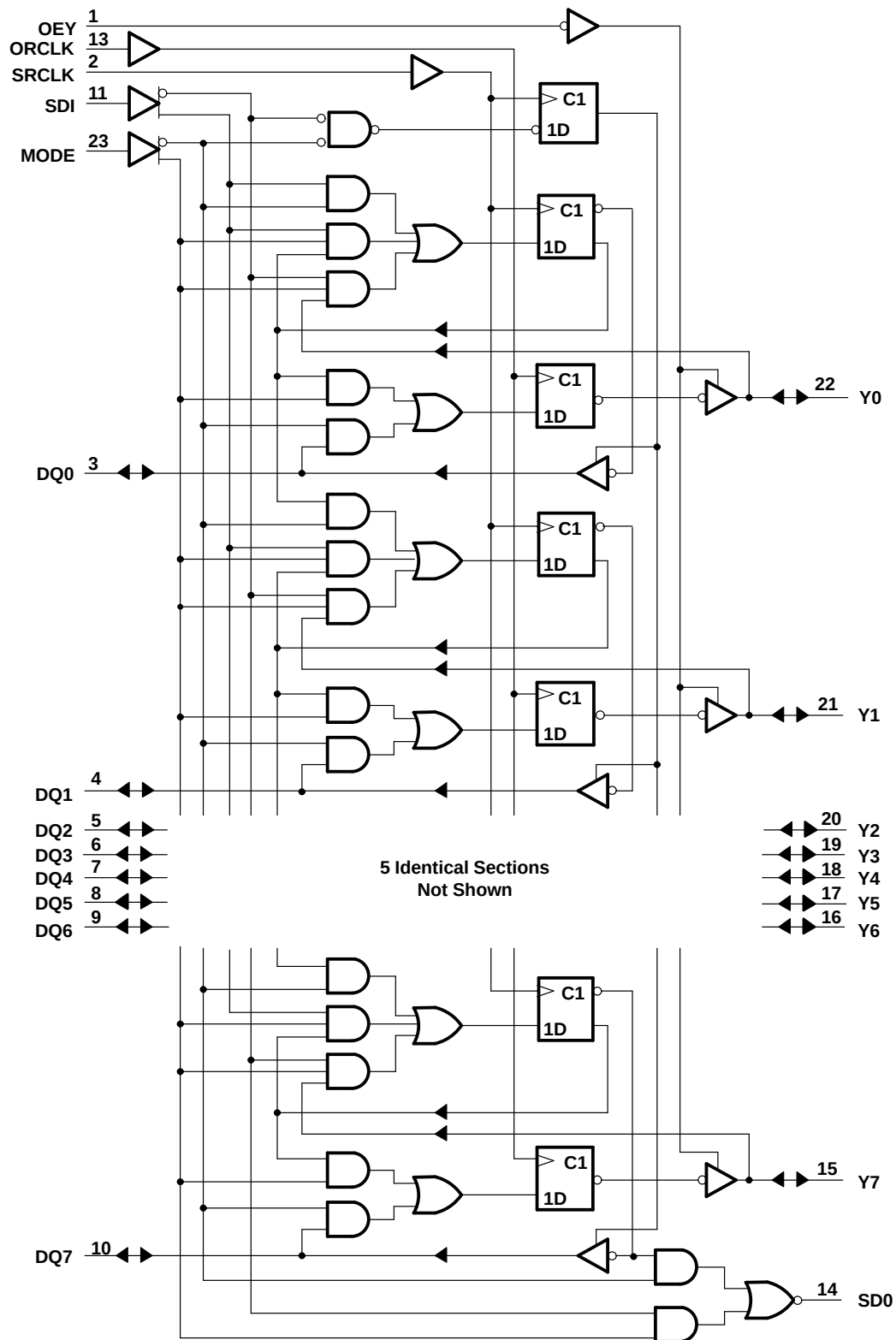
Pin numbers shown are for DW and NT packages.

SN74ALS29818

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

SN74ALS29818 gate-level logic diagram (positive logic)



Pin numbers shown are for DW and NT packages.

SN74ALS819, SN74ALS29818 8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

Function Tables
SN74ALS819

INPUTS				OUTPUT AND I/O			OPERATION OR FUNCTION
MODE	SDI	SRCLK	ORCLK	SDO	Y0–Y7 PE	DQ0–DQ7	
L	X	↑	X	SR7	OUTPUT	HI-Z	Serial input, shift right
H	L	↑	X	SDI (L)	OUTPUT	INPUT	Parallel load shadow register from DQ0–DQ7
H	L	↑	↑	SDI (L)	OUTPUT	INPUT	Parallel load shadow register and pipeline register from DQ0–DQ7
L X	X L	X X	↑ ↑	SR7 –	OUTPUT	INPUT	Load pipeline register from DQ0–DQ7
L	X	↑	↑	SR7	OUTPUT	INPUT	Load pipeline register from DQ0–DQ7 while shifting shadow register
H	H	No↑	↑	SDI (H)	OUTPUT	OUTPUT	Load pipeline register from shadow register
H	X	X	X	SDI	OUTPUT	–	Serial data in to serial data out
H	H	X	X	SDI (H)	OUTPUT	OUTPUT HOLD	Hold shadow register, enable DQ0–DQ7, transitions on SRCLK ignored
L X	X L	X X	X X	SR7 –	OUTPUT	HI-Z	Disable DQ0–DQ7 outputs

SN74ALS29818

INPUTS					OUTPUT AND I/O			OPERATION OR FUNCTION
MODE	O _{EY}	SDI	SRCLK	ORCLK	SDO	Y0–Y7	DQ0–DQ7	
L	X	X	↑	X	SR7	–	HI-Z	Serial input, shift right, disable DQ0–DQ7
H	H	L	↑	X	SDI (L)	INPUT	HI-Z	Parallel load shadow register from Y0–Y7, disable DQ0–DQ7
H	L	L	↑	No ↑	SDI (L)	OUTPUT	HI-Z	Parallel load shadow register from pipeline register, disable DQ0–DQ7
L	X	X	X	↑	SR7	–	INPUT [†]	Load pipeline register from DQ0–DQ7
L	X	X	↑	↑	SR7	–	INPUT [†]	Load pipeline register from DQ0–DQ7 while shifting shadow register
H	X	X	No ↑	↑	SDI	–	–	Load pipeline register from shadow register
H	X	X	X	X	SDI	–	–	Serial data in to serial data out
H	L	L	↑	↑	SDI (L)	OUTPUT	HI-Z	Exchange data between registers, DQ0–DQ7 disabled
H	X	H	X	X	SDI (H)	–	–	Hold shadow register, transitions on SRCLK do not effect shadow register
H	X	H	↑	X	SDI (H)	–	OUTPUT	Enable DQ0–DQ7 for parallel shadow register output

[†] The DQ0–DQ7 outputs must be disabled before applying data to DQ0–DQ7.

SN74ALS819, SN74ALS29818

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

absolute maximum ratings over operating free-air temperature range

Supply voltage, V_{CC}	7 V
Input voltage, any input or I/O port	5.5 V
Operating free-air temperature range	0°C to 70°C
Storage temperature range	–65°C to 150°C

recommended operating conditions

		MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			V
V_{IL}	Low-level input voltage			0.8	V
I_{OH}	High-level output current	Y0–Y7, PE		–3	mA
		All others		–1	
I_{OL}	Low-level output current	Y0–Y7, PE		24	mA
		All others		8	
t_w	Pulse duration	SRCLK high or low		25	ns
		ORCLK high or low		15	
t_{su}	Setup time before SRCLK↑	Y0–Y7 ('ALS29818)†		5	ns
		MODE		12	
		SDI		10	
		ORCLK ('ALS29818)†		40	
t_{su}	Setup time before ORCLK↑	DQ0–DQ7		8	ns
		MODE ('ALS29818)†		15	
		SRCLK‡		5	
t_h	Hold time after RCLK↑	Y0–Y7 ('ALS29818)†		5	ns
		MODE		2	
		SDI		0	
t_h	Hold time after ORCLK↑	DQ0–DQ7		2	ns
		MODE ('ALS29818) †		0	
		SDI ('ALS819)			
T_A	Operating free-air temperature	0		70	°C

† This setup time ensures that the shadow register will see stable data from the output register.

‡ This setup time ensures that the output register will see stable data from the shadow register.

SN74ALS819, SN74ALS29818

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

electrical characteristics over recommended operating temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP [†]	MAX	UNIT
V_{IK}		$V_{CC} = 4.75\text{ V}$, $I_I = -18\text{ mA}$			-1.2	V
V_{OH}	Y0–Y7, PE	$V_{CC} = 4.75\text{ V}$, $I_{OH} = -3\text{ mA}$	2.4	3.2		V
	All others	$V_{CC} = 4.75\text{ V}$, $I_{OH} = -1\text{ mA}$	2.4	3.2		
V_{OL}	Y0–Y7, PE	$V_{CC} = 4.75\text{ V}$, $I_{OL} = 24\text{ mA}$		0.35	0.5	V
	All others	$V_{CC} = 4.75\text{ V}$, $I_{OL} = 8\text{ mA}$		0.35	0.5	
I_I		$V_{CC} = 5.25\text{ V}$, $V_I = 5.5\text{ V}$			0.1	mA
$I_{IH}^{\ddagger}$		$V_{CC} = 5.25\text{ V}$, $V_I = 2.4\text{ V}$			20	μA
$I_{IL}^{\ddagger}$	MODE, SDI	$V_{CC} = 5.25\text{ V}$, $V_I = 0.5\text{ V}$			-0.2	mA
	All others				-0.1	
$I_{OS}^{\S}$		$V_{CC} = 5.25\text{ V}$, $V_O = 0$	-75		-250	mA
I_{CC}	'ALS819	$V_{CC} = 5.25\text{ V}$, See Note 1		65	100	mA
	'ALS29818			85	120	

[†] All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state current.

[§] Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 1: I_{CC} is measured with all 3-state outputs in the high-impedance state.

SN74ALS819, SN74ALS29818

8-BIT DIAGNOSTICS/PIPELINE REGISTERS

SDAS105A – JANUARY 1986 – REVISED OCTOBER 1986

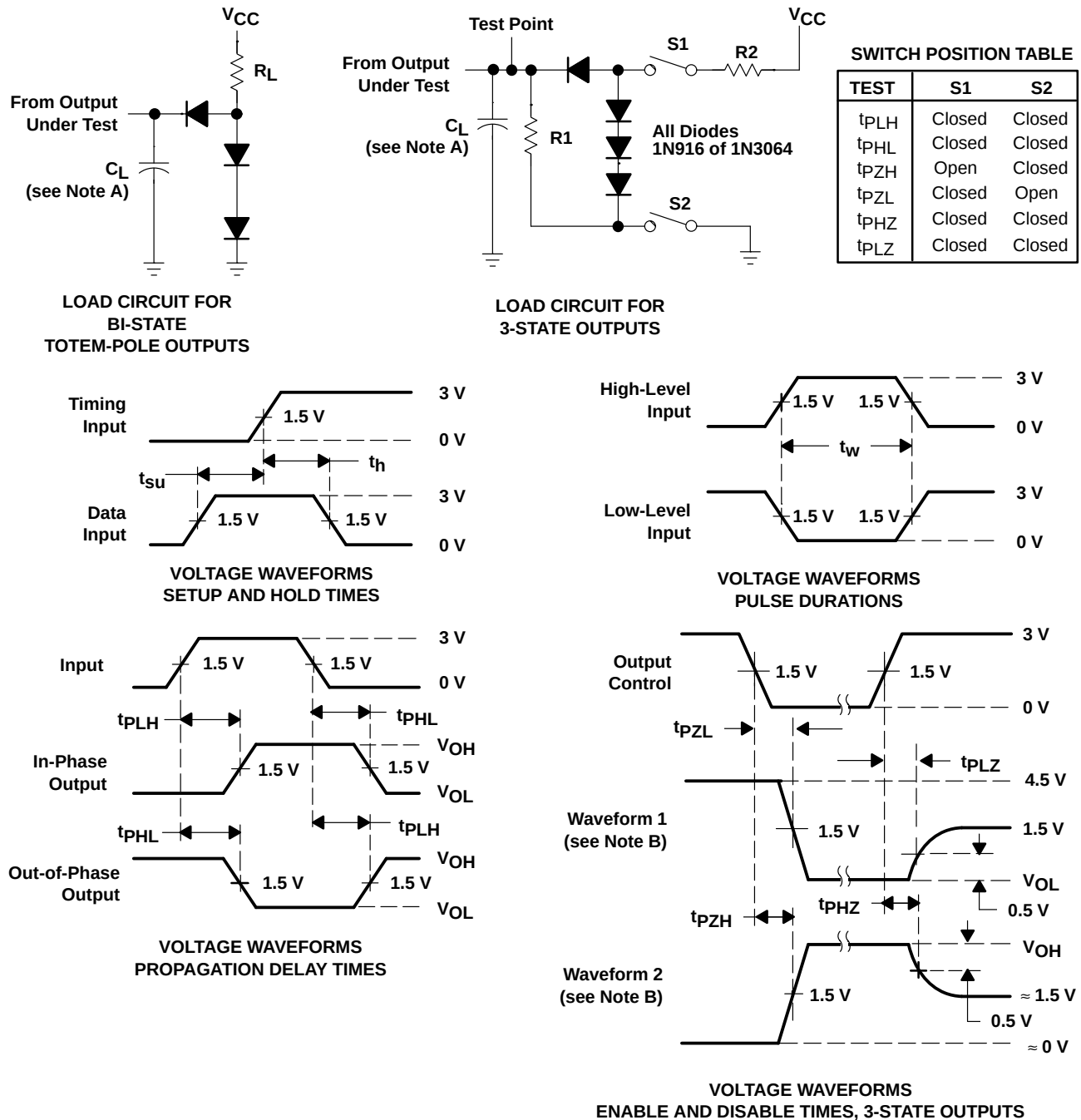
SN74ALS819 switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V _{CC} = 5 V, C _L = 50 pF, T _A = 25°C			V _{CC} = 4.75 V to 5.25 V, C _L = 50 pF, T _A = 0°C to 70°C		UNIT
				MIN	TYP	MAX	MIN	MAX	
t _{PLH}	MODE	SDO	R _L = 2 kΩ		10	14	4	16	ns
t _{PHL}					8	11	4	13	
t _{PLH}	SDI	SDO	R _L = 2 kΩ		13	17	7	20	ns
t _{PHL}					10	14	5	16	
t _{PLH}	ORCLK	Y0–Y7	R _L = 2 kΩ		10	14	4	16	ns
t _{PHL}					9	12	4	14	
t _{PLH}	ORCLK	PE	R _L = 2 kΩ		25	32	10	45	ns
t _{PHL}					16	20	8	25	
t _{PLH}	SRCLK	SDO	R _L = 2 kΩ		14	18	7	22	ns
t _{PHL}					9	12	5	15	
t _{PZH}	MODE or SDI	DQ0–DQ7	R1 = 5 kΩ, R2 = 2 kΩ		11	15	5	17	ns
t _{PZL}					14	19	8	20	
t _{PHZ}	MODE or SDI	DQ0–DQ7	R1 = 5 kΩ, R2 = 2 kΩ		48	75	23	80	ns
t _{PLZ}					21	29	12	35	

SN74ALS29818 switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	V _{CC} = 5 V, C _L = 50 pF, T _A = 25°C			V _{CC} = 4.75 V to 5.25 V, C _L = 50 pF, T _A = 0°C to 70°C		UNIT
				MIN	TYP	MAX	MIN	MAX	
t _{PLH}	MODE	SDO	R _L = 2 kΩ		10	14		16	ns
t _{PHL}					10	14		16	
t _{PLH}	SDI	SDO	R _L = 2 kΩ		10	14		16	ns
t _{PHL}					10	14		16	
t _{PLH}	ORCLK	Y0–Y7	R _L = 2 kΩ		10	12		13	ns
t _{PHL}					10	12		13	
t _{PLH}	SRCLK	SDO	R _L = 2 kΩ		12	18		25	ns
t _{PHL}					9	14		20	
t _{PZH}	SRCLK	DQ0–DQ7	R1 = 5 kΩ, R2 = 2 kΩ		13	20		25	ns
t _{PZL}					16	25		30	
t _{PHZ}	SRCLK	DQ0–DQ7	R1 = 5 kΩ, R2 = 2 kΩ		52	80		85	ns
t _{PLZ}					21	33		45	
t _{PHZ}	$\overline{\text{OEY}}$	Y0–Y7	R1 = 5 kΩ, R2 = 2 kΩ		12	19		25	ns
t _{PLZ}					8	12		15	
t _{PZH}	$\overline{\text{OEY}}$	Y0–Y7	R1 = 5 kΩ, R2 = 2 kΩ		7	12		15	ns
t _{PZL}					11	15		15	

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r = 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.

Figure 1

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.